



Certified Reference Material

Certificate of Analysis



ISO/IEC 17025:2017



Product ID: IARM-FE254SMO-21

Product Description: Stainless Steel, Austenitic, Alloy 254SMO/S31254

Revision No.: 000 Revision Date: 02/27/2022

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

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Certified Values listed in wt.% with associated uncertainties													
ΑI	0.022	±0.002	Cr	19.7	±0.1	Ni	18.1	±0.1	Sn	0.0041	± 0.0004		
As	0.0044	± 0.0004	Cu	0.77	±0.01	0	0.0025	± 0.0003	Ti	0.004	± 0.001		
В	0.0009	± 0.0006	Fe	53.7	±0.3	Р	0.022	±0.001	٧	0.052	± 0.002		
С	0.017	±0.001	Mn	0.892	± 0.005	S	0.0010	± 0.0003	W	0.041	± 0.002		
Ca	0.0024	± 0.0003	Mo	6.09	± 0.04	Sb	0.0017	±0.0008					
Co	0.118	± 0.003	N	0.200	±0.007	Si	0.301	±0.007					

Indicative Values listed in ppm Ta 46 Zr 17

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (Unom). Uncertainty of the material is calculated by equation 2, where H=Uhom, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1.
$$N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$
 2. $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- Applied Technical Services Marietta, GA
- Avon Specialty Metals Gloucester, England
- Dirats Laboratories Westfield, MA FAG Laboratories - Liverpool NY
- Genitest Inc Montreal, Canada
- IMR Test Labs Lansing, NY
 - Laboratory Testing, Inc. Hatfield, PA

 - Lucid Laboratories Pvt Ltd Hvderabad, India Lukasiewicz Instytut Metalurgii Zelaza - Gliwice, Poland
 - LGC Standards Manchester, NH
- New Hampshire Materials Laboratory Inc Somersworth, NH
- NSL Analytical Services Cleveland, OH
- Scrooby's Laboratory Service Pty Ltd Benoni, South Africa
- SGS MSi Melrose Park II
- Sheffield Assay Office Sheffield, England

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use.

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Chuck Goudreau, Certifying Officer

February 27, 2023 **Certification Date**



ISO 17034 Accredited: Reference Materials Producer, Certificate # 2848.02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	As	В	С	Ca	Co	Cr	Cu	Fe	Mn	Мо	N	Nb
1	0.0170	0.0038	0.0003	0.0141	0.0017	0.0970	19.27	0.7130	53.12	0.8750	5.8790	0.1844	0.0003
2	0.0180	0.0041	0.0004	0.0142	0.0020	0.1010	19.30	0.7180	53.20	0.8768	5.9300	0.1861	0.0010
3	0.0180	0.0045	0.0006	0.0145	0.0022	0.1100	19.38	0.7210	53.51	0.8790	5.9800	0.1900	0.0013
4	0.0190	0.0046	0.0012	0.0150	0.0023	0.1100	19.53	0.7360	53.68	0.8800	5.9810	0.1960	0.0066
5	0.0198	0.0046	0.0015	0.0160	0.0024	0.1130	19.58	0.7410	53.87	0.8821	5.9900	0.1970	0.0073
6	0.0202	0.0050	0.0016	0.0166	0.0026	0.1140	19.59	0.7410	54.00	0.8830	6.0497	0.1980	0.0078
7	0.0210	<0.005	<0.0005	0.0167	0.0026	0.1153	19.61	0.7430	54.01	0.8860	6.0540	0.2000	0.0080
8	0.0211	<0.0050	<0.0010	0.0170	0.0027	0.1163	19.61	0.7480	54.07	0.8878	6.0633	0.2020	0.0080
9	0.0213	<0.01	<0.005	0.0171	0.0029	0.1177	19.65	0.7507	54.21	0.8900	6.0680	0.2077	0.0090
10	0.0223	<0.01	< 0.005	0.0179	< 0.002	0.1187	19.70	0.7613		0.8928	6.0794	0.2100	0.0096
11	0.0230	<0.01	<0.01	0.0180	< 0.002	0.1200	19.72	0.7640		0.8950	6.0800	0.2110	0.0100
12	0.0238		<0.01	0.0182	<0.002	0.1200	19.75	0.7676		0.8960	6.1070	0.2191	0.0107
13	0.0240			0.0184	< 0.005	0.1200	19.76	0.7754		0.8975	6.1080		0.0113
14	0.0250			0.0200	<0.0050	0.1209	19.78	0.7809		0.8980	6.1110		0.0134
15	0.0251			0.0210	< 0.0050	0.1210	19.79	0.7832		0.8993	6.1300		0.0198
16	0.0256			0.0213	<0.01	0.1230	19.82	0.7840		0.9004	6.1453		<0.0005
17	0.0263					0.1230	19.87	0.7860		0.9010	6.1600		< 0.005
18	0.0270					0.1239	19.89	0.7897		0.9066	6.1600		<0.01
19	0.0275					0.1240	20.00	0.7980		0.9160	6.1600		
20	<0.01					0.1248	20.08	0.8060			6.1610		
21						0.1258	20.09	0.8100			6.1884		
22						0.1280	20.10	0.8160			6.2084		
23						0.1284	20.12	0.8250			6.2330		
Mean	0.0224	0.0044	0.0009	0.0172	0.0024	0.1181	19.74	0.7678	53.74	0.8917	6.0881	0.2001	0.0083
STDV	0.0032	0.0004	0.0006	0.0022	0.0004	0.0079	0.24	0.0322	0.39	0.0109	0.0899	0.0105	0.0050
Certified	0.022	0.0044	0.0009	0.017	0.0024	0.118	19.7	0.77	53.7	0.892	6.09	0.200	(0.0083)
U _{CRM}	0.002	0.0004	0.0006	0.001	0.0003	0.003	0.1	0.01	0.3	0.005	0.04	0.007	,
Methods	O,G,IM,I,X	I,G,IM	I,O,G,IM	C,G,O	I,G,IM,O,X	I,O,G,IM,X	I,O,G,X	I,G,O,X	I,O,X	O,I,G,X	I,G,O,X	F,0	I,G,IM,X,O

	Ni	0	Р	S	Sb	Si	Sn	Та	Ti	V	W	Zr
1	17.43	0.0020	0.0160	0.0004	0.0008	0.2740	0.0026	0.0001	0.0009	0.0451	0.0330	0.0001
2	17.64	0.0023	0.0190	0.0005	0.0010	0.2750	0.0037	0.0011	0.0019	0.0465	0.0336	0.0008
3	17.66	0.0024	0.0196	0.0005	0.0011	0.2765	0.0037	0.0015	0.0020	0.0479	0.0360	0.0012
4	17.80	0.0024	0.0200	0.0007	0.0013	0.2800	0.0037	0.0155	0.0024	0.0492	0.0367	0.0026
5	17.90	0.0025	0.0204	0.0007	0.0021	0.2860	0.0038	<0.00005	0.0024	0.0506	0.0379	0.0036
6	17.97	0.0028	0.0209	0.0008	0.0023	0.2900	0.0039	<0.0005	0.0026	0.0506	0.0380	< 0.0005
7	18.01	0.0031	0.0209	0.0009	0.0030	0.2918	0.0040	<0.0010	0.0030	0.0510	0.0380	< 0.0010
8	18.08		0.0210	0.0009	<0.0010	0.2920	0.0041	<0.005	0.0036	0.0510	0.0380	<0.002
9	18.09		0.0218	0.0014	<0.002	0.3000	0.0041	<0.0050	0.0043	0.0510	0.0385	< 0.002
10	18.12		0.0220	0.0015	<0.002	0.3003	0.0044	<0.01	0.0048	0.0510	0.0389	< 0.002
11	18.12		0.0222	0.0016	<0.002	0.3004	0.0045	<0.01	0.0050	0.0510	0.0390	< 0.005
12	18.14		0.0226	0.0021	<0.0020	0.3040	0.0046		0.0050	0.0518	0.0410	< 0.005
13	18.15		0.0233	< 0.001	<0.01	0.3060	0.0050		0.0061	0.0519	0.0410	<0.01
14	18.16		0.0234	<0.0010	<0.01	0.3070	0.0060		0.0067	0.0519	0.0430	<0.01
15	18.23		0.0240	<0.002		0.3080	<0.002		0.0069	0.0520	0.0440	
16	18.24		0.0240			0.3097	<0.002		0.0086	0.0520	0.0450	
17	18.26		0.0241			0.3100	<0.002		< 0.005	0.0520	0.0458	
18	18.27		0.0245			0.3100	< 0.0050			0.0527	0.0460	
19	18.27		0.0250			0.3127	<0.01			0.0530	0.0462	
20	18.28		0.0261			0.3210	<0.01			0.0570	0.0464	
21	18.35		0.0270			0.3279				0.0600	0.0477	
22	18.41					0.3360				0.0610	0.0508	
23												
Mean	18.07	0.0025	0.0223	0.0010	0.0017	0.3008	0.0041	0.0046	0.0041	0.0518	0.0411	0.0017
STDV	0.25	0.0003	0.0026	0.0005	0.0008	0.0166	0.0008	0.0073	0.0022	0.0037	0.0048	0.0014
Certified	18.1	0.0025	0.022	0.0010	0.0017	0.301	0.0041	(0.0046)	0.004	0.052	0.041	(0.0017)
U _{CRM}	0.1	0.0003	0.001	0.0003	0.0008	0.007	0.0004		0.001	0.002	0.002	
Methods	I,G,O,X	F	I,O,G,IM,X	C,G,O,W,X	I,G,IM,O,X	O,I,G,IM,X	O,I,G,IM,X	I,G,IM	I,O,G,IM,X	I,G,IM,O,X	I,O,G,IM,X	I,O,G,IM,X

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES